

TPS20xxB-Q1 電流制限パワー・ディストリビューション・スイッチ

1 特長

- 車載アプリケーション認定済み
- 下記内容で AEC-Q100 認定済み:
 - デバイス温度グレード 1: -40°C ~ 125°C の動作時周囲温度範囲
 - デバイス HBM ESD 分類レベル 2
 - デバイス CDM ESD 分類レベル C6
 - デバイス MM ESD 分類レベル M0
- 105mΩ のハイサイド MOSFET
- 500mA の連続電流
- 過熱および短絡保護
- 正確な電流制限: 0.75A (最小値)、1.25A (最大値)
- 動作範囲: 2.7V ~ 5.5V
- 0.6ms の標準立ち上がり時間
- 低電圧誤動作防止
- デグリッチ・フォルト・レポート (\overline{OC})
- 電源投入時の \overline{OC} グリッチなし
- スタンバイ時の最大電源電流: 1μA (シングル、デュアル) または 2μA (トリプル、クワッド)
- 双方向スイッチ
- UL はファイル番号 E169910 で認識されています

2 アプリケーション

- 大きな容量性負荷
- 短絡保護

3 概要

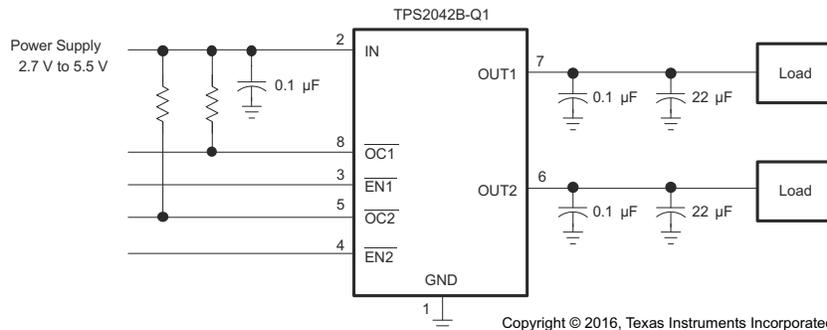
TPS20xxB-Q1 パワー・ディストリビューション・スイッチは、大きな容量性負荷があり、短絡が発生しやすいアプリケーションを対象としています。これらのデバイスは、複数のパワー・スイッチを 1 つのパッケージに搭載する必要のあるパワー・ディストリビューション・システム向けに、105mΩ の N チャネル MOSFET パワー・スイッチを内蔵しています。各スイッチは、ロジック・イネーブル入力によって制御されます。ゲート・ドライブは、内部チャージ・ポンプによって供給され、スイッチング中の電流サージを最小限に抑えるために、パワー・スイッチの立ち上がり時間と立ち下がり時間を制御するように設計されています。チャージ・ポンプには外付け部品が不要で、最低 2.7V の電源で動作できます。

出力負荷が電流制限スレッショルドを超えた場合、または短絡が存在する場合、デバイスは定電流モードに切り替えて過電流 (\overline{OCx}) ロジック出力を Low にすることで、出力電流を安全なレベルに制限します。連続的に大きな過負荷と短絡が発生すると、スイッチの消費電力が増加し、接合部温度が上昇すると、熱保護回路によってスイッチがシャットオフされ、損傷を防止します。デバイスの温度が十分に低下すると、自動的にサーマル・シャットダウンからの回復が行われます。内部回路により、有効な入力電圧が印加されるまでスイッチがオフに維持されます。このパワー・ディストリビューション・スイッチは、電流制限を 1A (標準値) に設定するように設計されています。

製品情報(1)

部品番号	パッケージ	本体サイズ (公称)
TPS2041B-Q1	SOT-23 (5)	2.80mm × 2.90mm
TPS2042B-Q1、 TPS2051B-Q1	SOIC (8)	4.90mm × 6.00mm

(1) 利用可能なパッケージについては、このデータシートの末尾にある注文情報を参照してください。



代表的なアプリケーション回路図



Table of Contents

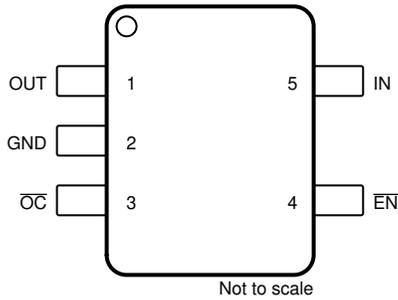
1 特長	1	9 Application and Implementation	13
2 アプリケーション	1	9.1 Application Information.....	13
3 概要	1	9.2 Typical Applications.....	13
4 Revision History	2	10 Power Supply Recommendations	20
5 Pin Configuration and Functions	3	11 Layout	21
6 Specifications	4	11.1 Layout Guidelines.....	21
6.1 Absolute Maximum Ratings.....	4	11.2 Layout Example.....	21
6.2 ESD Ratings.....	4	11.3 Thermal Considerations.....	21
6.3 Recommended Operating Conditions.....	5	12 Device and Documentation Support	22
6.4 Thermal Information.....	5	12.1 Related Links.....	22
6.5 Electrical Characteristics.....	5	12.2 ドキュメントの更新通知を受け取る方法.....	22
6.6 Typical Characteristics.....	7	12.3 サポート・リソース.....	22
7 Parameter Measurement Information	9	12.4 Trademarks.....	22
8 Detailed Description	10	12.5 静電気放電に関する注意事項.....	22
8.1 Overview.....	10	12.6 用語集.....	22
8.2 Functional Block Diagrams.....	10	13 Mechanical, Packaging, and Orderable	
8.3 Feature Description.....	11	Information	22
8.4 Device Functional Modes.....	12		

4 Revision History

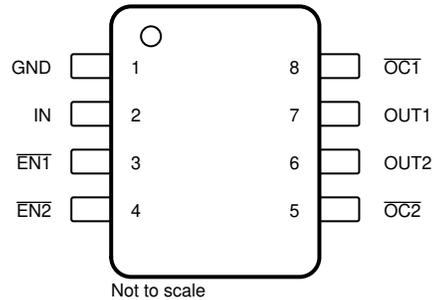
資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision C (September 2016) to Revision D (October 2020)	Page
• 文書全体にわたって表、図、相互参照の採番方法を更新.....	1
• 「特長」一覧の「70mΩ ハイサイド MOSFET」を「105mΩ ハイサイド MOSFET」に変更.....	1
• 「概要」セクションの「70mΩ ハイサイド MOSFET」を「105mΩ ハイサイド MOSFET」に変更.....	1
• Updated $r_{DS(ON)}$ TYP and MAX values in the <i>Electrical Characteristics</i> table.....	5
• Updated 図 6-9	7
• Changed "70-mΩ High-Side MOSFET" to "105-mΩ High-Side MOSFET" in the <i>Overview</i> section.....	10
Changes from Revision B (October 2011) to Revision C (September 2016)	Page
• 「ESD 定格」表、「機能説明」セクション、「デバイスの機能モード」セクション、「アプリケーションと実装」セクション、「電源に関する推奨事項」セクション、「レイアウト」セクション、「デバイスおよびドキュメントのサポート」セクション、「メカニカル、パッケージ、および注文情報」セクションを追加.....	1
• 「注文情報」表を削除 (データシートの末尾にある POA を参照)	1
• 汎用スイッチ・カタログの画像を削除.....	1
• AEC-Q100 認定の簡条書きを追加.....	1
• Added <i>Thermal Information</i> table.....	5
• Deleted <i>Dissipation Ratings</i> section	7
• Combined Functional Block Diagrams for TPS2041B-Q1 and TPS2051B-Q1 as they are the same.....	10
Changes from Revision A (June 2010) to Revision B (October 2011)	Page
• 注文部品番号を TPS2041QBVRQ1 から TPS2041BQDBVRQ1 に変更.....	1
Changes from Revision * (November 2007) to Revision A (June 2010)	Page
• TPS2041B-Q1 のデバイス情報を追加.....	1

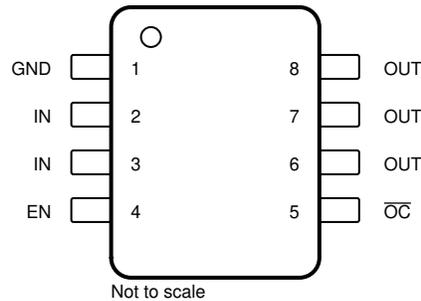
5 Pin Configuration and Functions



✎ 5-1. TPS2041B-Q1 DBV Package 5-Pin SOT-23 Top View



✎ 5-2. TPS2042B-Q1 D Package 8-Pin SOIC Top View



✎ 5-3. TPS2051B-Q1 D Package 8-Pin SOIC Top View

表 5-1. Pin Functions: TPS2041B-Q1

PIN		TYPE	DESCRIPTION
NAME	NO.		
EN	4	I	Enable input, logic low turns on power switch
GND	2	GND	Ground
IN	5	PWR	Supply input voltage
OC	3	O	Overcurrent, open-drain output, active low
OUT	1	O	Power-switch output

表 5-2. Pin Functions: TPS2042B-Q1

PIN		TYPE	DESCRIPTION
NAME	NO.		
EN1	3	I	Enable input, logic low turns on power switch IN-OUT1
EN2	4	I	Enable input, logic low turns on power switch IN-OUT2
GND	1	GND	Ground
IN	2	PWR	Supply input voltage
OC1	8	O	Overcurrent, open-drain output, active low, IN-OUT1
OC2	5	O	Overcurrent, open-drain output, active low, IN-OUT2

表 5-2. Pin Functions: TPS2042B-Q1 (continued)

PIN		TYPE	DESCRIPTION
NAME	NO.		
OUT1	7	O	Power-switch output, IN-OUT1
OUT2	6	O	Power-switch output, IN-OUT2

表 5-3. Pin Functions: TPS2051B-Q1

PIN		TYPE	DESCRIPTION
NAME	NO.		
EN	4	I	Enable input, logic high turns on power switch
GND	1	GND	Ground
IN	2, 3	PWR	Supply input voltage
\overline{OC}	5	O	Overcurrent open-drain output, active low
OUT	6, 7, 8	O	Power-switch output

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range unless otherwise noted⁽¹⁾

		MIN	MAX	UNIT
Input voltage ⁽²⁾	IN	-0.3	6	V
Output voltage ⁽²⁾	OUT, OUTx	-0.3	6	V
Input voltage	ENx, EN	-0.3	6	V
Voltage, $V_{I(\overline{OC})}$, $V_{I(\overline{OCx})}$	\overline{OC} , \overline{OCx}	-0.3	6	V
Continuous output current		Internally limited		
Continuous total power dissipation		See ESD Ratings		
Operating virtual-junction temperature, T_j		-40	125	°C
Storage temperature, T_{stg}		-65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages are with respect to GND.

6.2 ESD Ratings

		VALUE	UNIT
TPS2041B-Q1 in DBV Package and TPS2042B-Q1 in D package			
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 ⁽¹⁾	±2500
		Charged-device model (CDM), per AEC Q100-011	±1500
		Machine model (MM), per AEC Q100-003	±50
TPS2051B-Q1 in D package			
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 ⁽¹⁾	±2000
		Charged-device model (CDM), per AEC Q100-011	±1500
		Machine model (MM), per AEC Q100-003	±50

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

		MIN	MAX	UNIT
$V_{I(IN)}$	Input voltage (IN)	2.7	5.5	V
$V_{I(EN\bar{x})}$, $V_{I(EN)}$	Input voltage ($EN\bar{x}$, EN)	0	5.5	V
$I_{O(OUT)}$, $I_{O(OUTx)}$	Continuous output current (OUT, OUTx)	0	500	mA
T_J	Operating virtual-junction temperature	-40	125	°C

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾	TPS2041B-Q1	TPS2042B-Q1	TPS2051B-Q1	UNIT	
	DBV (SOT-23)	D (SOIC)	D (SOIC)		
	5 PINS	8 PINS	8 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	224.1	117.2	124.5	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	131.2	63.3	72.7	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	55.4	57.5	64.9	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	19.2	15.3	24.7	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	54.3	37	64.4	°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Electrical Characteristics

over recommended operating junction temperature range, $V_{I(IN)} = 5.5$ V, $I_O = 0.5$ A, $V_{I(EN\bar{x})} = 0$ V (unless otherwise noted)

PARAMETER		TEST CONDITIONS ⁽¹⁾		MIN	TYP	MAX	UNIT
POWER SWITCH							
$r_{DS(ON)}$	Static drain-source on-state resistance, 5-V or 3.3-V operation	$V_{I(IN)} = 5$ V or 3.3 V, $I_O = 0.5$ A	$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$		105	160	mΩ
	Static drain-source on-state resistance, 2.7-V operation ⁽²⁾	$V_{I(IN)} = 2.7$ V, $I_O = 0.5$ A	$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$		110	175	
t_r	Rise time, output ⁽²⁾	$V_{I(IN)} = 5.5$ V $V_{I(IN)} = 2.7$ V	$C_L = 1$ μF, $R_L = 10$ Ω $T_J = 25^\circ\text{C}$		0.6 0.4	1.5 1	ms
t_f	Fall time, output ⁽²⁾	$V_{I(IN)} = 5.5$ V $V_{I(IN)} = 2.7$ V	$C_L = 1$ μF, $R_L = 10$ Ω $T_J = 25^\circ\text{C}$		0.05 0.05	0.5 0.5	
ENABLE INPUT (EN, $EN\bar{x}$)							
V_{IH}	High-level input voltage	2.7 V $\leq V_{I(IN)} \leq 5.5$ V		2			V
V_{IL}	Low-level input voltage	2.7 V $\leq V_{I(IN)} \leq 5.5$ V				0.8	
I_I	Input current	$V_{I(EN\bar{x})} = 0$ V or 5.5 V		-0.5		0.5	μA
t_{on}	Turnon time ⁽²⁾	$C_L = 100$ μF, $R_L = 10$ Ω				3	ms
t_{off}	Turnoff time ⁽²⁾	$C_L = 100$ μF, $R_L = 10$ Ω				10	
CURRENT LIMIT							
I_{OS}	Short-circuit output current	$V_{I(IN)} = 5$ V, OUT connected to GND, device enabled into short-circuit	$T_J = 25^\circ\text{C}$	0.65	1	1.25	A
			$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	0.6	1	1.3	
SUPPLY CURRENT (TPS2041B-Q1, TPS2051B-Q1)							
Supply current, low-level output	No load on OUT, $V_{I(EN)} = 5.5$ V or $V_{I(EN)} = 0$ V	$T_J = 25^\circ\text{C}$		0.5	1	μA	
		$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$		0.5	5		
Supply current, high-level output	No load on OUT, $V_{I(EN)} = 0$ V or $V_{I(EN)} = 5.5$ V	$T_J = 25^\circ\text{C}$		43	60	μA	
		$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$		43	70		
Leakage current	OUT connected to ground, $V_{I(EN)} = 5.5$ V or $V_{I(EN)} = 0$ V	$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$		1		μA	
Reverse leakage current	$V_{I(OUTx)} = 5.5$ V, IN = ground ⁽²⁾	$T_J = 25^\circ\text{C}$		0		μA	

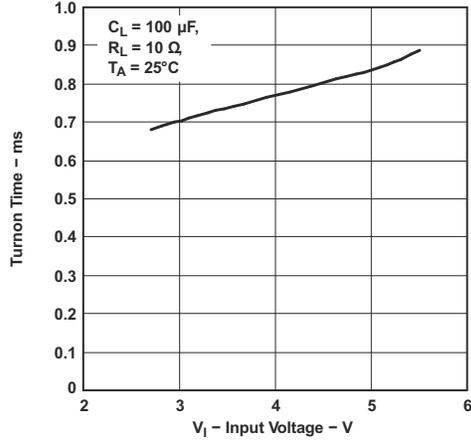
6.5 Electrical Characteristics (continued)

over recommended operating junction temperature range, $V_{I(IN)} = 5.5\text{ V}$, $I_O = 0.5\text{ A}$, $V_{I(EN\bar{x})} = 0\text{ V}$ (unless otherwise noted)

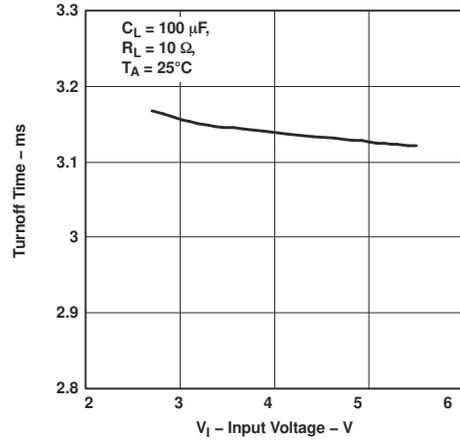
PARAMETER	TEST CONDITIONS ⁽¹⁾	MIN	TYP	MAX	UNIT
SUPPLY CURRENT (TPS2042B-Q1)					
Supply current, low-level output	No load on OUT, $V_{I(EN\bar{x})} = 5.5\text{ V}$	$T_J = 25^\circ\text{C}$	0.5	1	μA
		$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	0.5	5	
Supply current, high-level output	No load on OUT, $V_{I(EN\bar{x})} = 0\text{ V}$	$T_J = 25^\circ\text{C}$	50	70	μA
		$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$	50	90	
Leakage current	OUT connected to ground, $V_{I(EN\bar{x})} = 5.5\text{ V}$	$-40^\circ\text{C} \leq T_J \leq 125^\circ\text{C}$		1	μA
Reverse leakage current	$V_{I(OUTx)} = 5.5\text{ V}$, IN = ground ⁽²⁾	$T_J = 25^\circ\text{C}$		0.2	μA
UNDERVOLTAGE LOCKOUT					
Low-level input voltage, IN, INx		2		2.5	V
Hysteresis, IN, INx	$T_J = 25^\circ\text{C}$		75		mV
OVERCURRENT ($\overline{\text{OC}}$, $\overline{\text{OCx}}$)					
Output low voltage, $V_{OL}(\overline{\text{OCx}})$	$I_{O(\overline{\text{OCx}})} = 5\text{ mA}$			0.4	V
OFF-state current ⁽²⁾	$V_{O(\overline{\text{OCx}})} = 5\text{ V}$ or 3.3 V			1	μA
$\overline{\text{OC}}$ deglitch ⁽²⁾	$\overline{\text{OCx}}$ assertion or deassertion	4	8	15	ms
THERMAL SHUTDOWN⁽³⁾					
Thermal shutdown threshold ⁽²⁾		135			$^\circ\text{C}$
Recovery from thermal shutdown ⁽²⁾		125			$^\circ\text{C}$
Hysteresis ⁽²⁾			10		$^\circ\text{C}$

- (1) Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be accounted for separately.
- (2) Specified by design.
- (3) The thermal shutdown only reacts under overcurrent conditions.

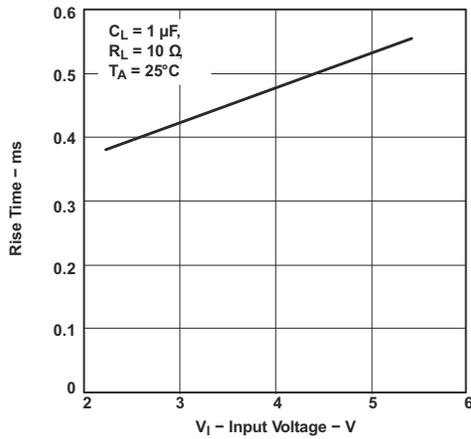
6.6 Typical Characteristics



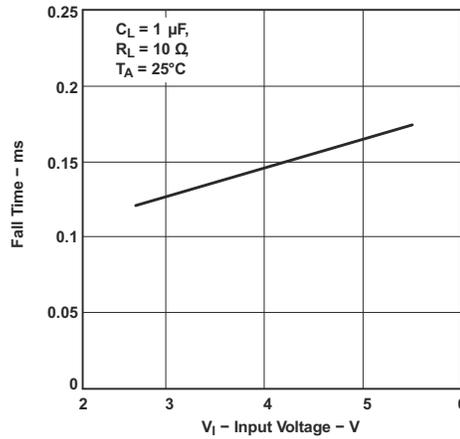
6-1. Turnon Time vs Input voltage



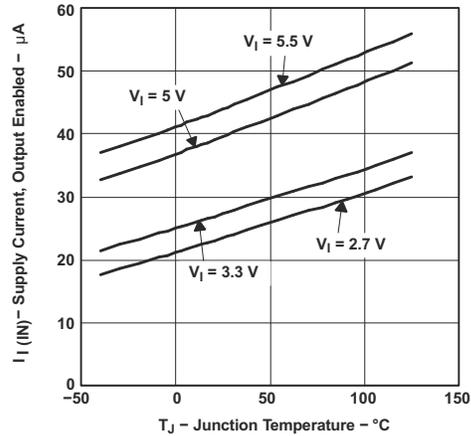
6-2. Turnoff Time vs Input Voltage



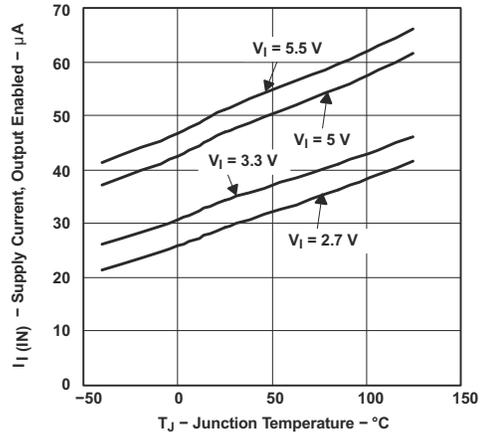
6-3. Rise Time vs Input Voltage



6-4. Fall Time vs Input Voltage

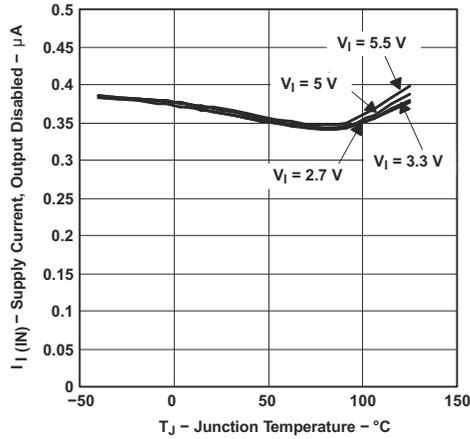


6-5. TPS2041B-Q1 and TPS2051B-Q1 Supply Current, Output Enabled vs Junction Temperature

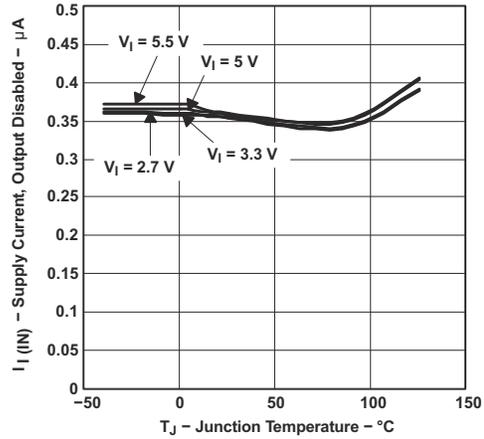


6-6. TPS2042B-Q1 Supply Current, Output Enabled vs Junction Temperature

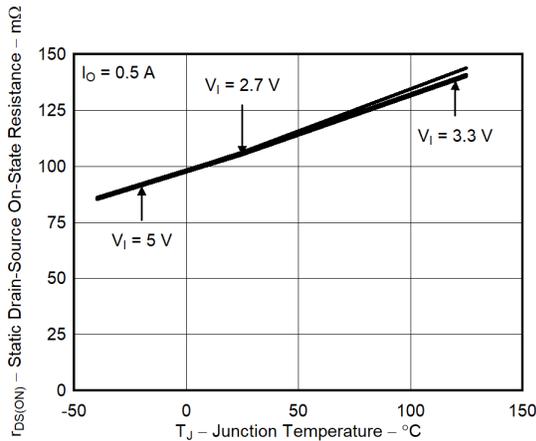
6.6 Typical Characteristics (continued)



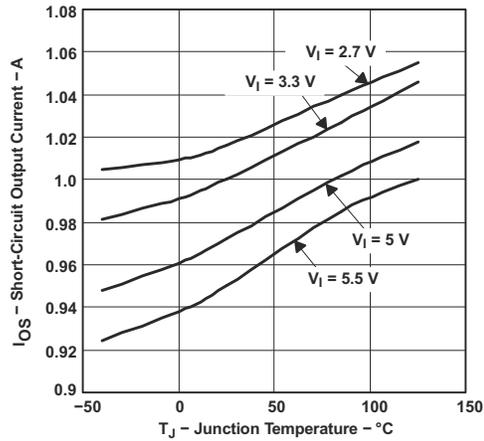
6-7. TPS2041B-Q1 and TPS2051B-Q1 Supply Current, Output Disabled vs Junction Temperature



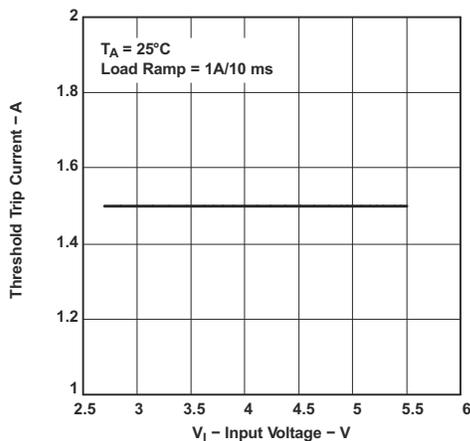
6-8. TPS2042B-Q1 Supply Current, Output Disabled vs Junction Temperature



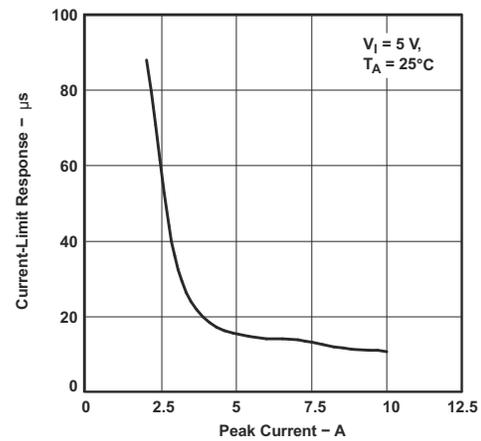
6-9. Static Drain-Source ON-state Resistance vs Junction Temperature



6-10. Short-Circuit Output Current vs Junction Temperature

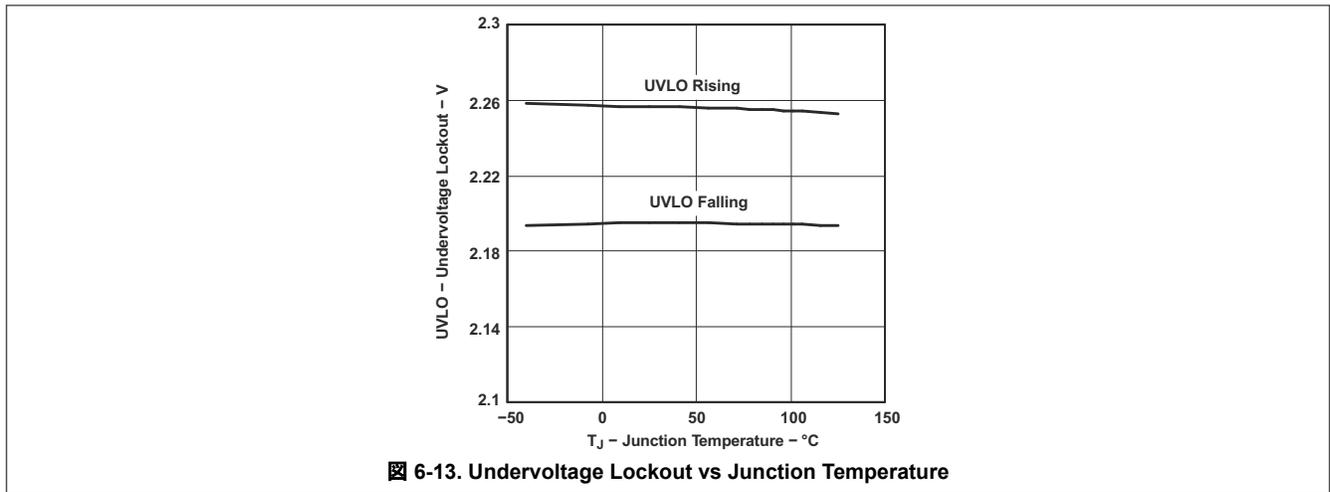


6-11. Threshold Trip Current vs Input Voltage

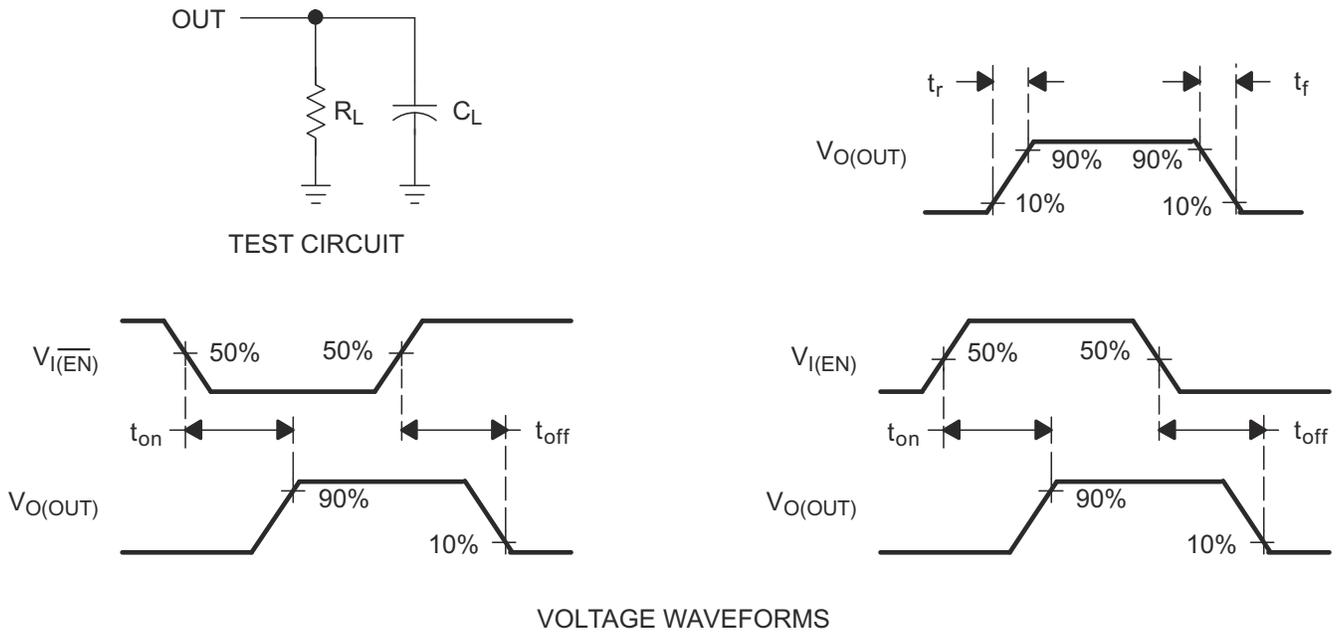


6-12. Current-Limit Response vs Peak Current

6.6 Typical Characteristics (continued)



7 Parameter Measurement Information



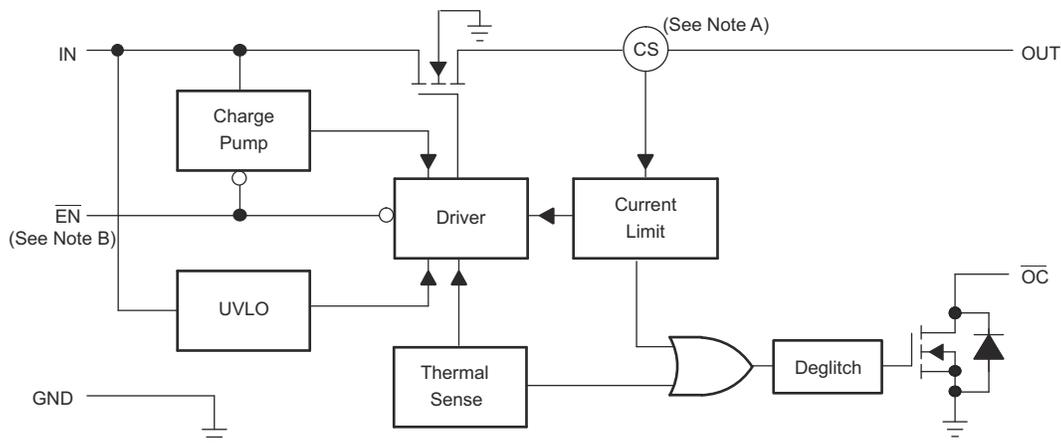
7-1. Test Circuit and Voltage Waveforms

8 Detailed Description

8.1 Overview

The TPS20xxB-Q1 devices are current-limited, power-distribution switches providing 0.5-A continuous-load current. These devices incorporate 105-mΩ N-channel MOSFET power switches for power-distribution systems that require multiple power switches in a single package. A gate driver is provided by an internal charge pump designed to minimize current surges during switching. The charge pump requires no external components and allows operation supplies as low as 2.7 V.

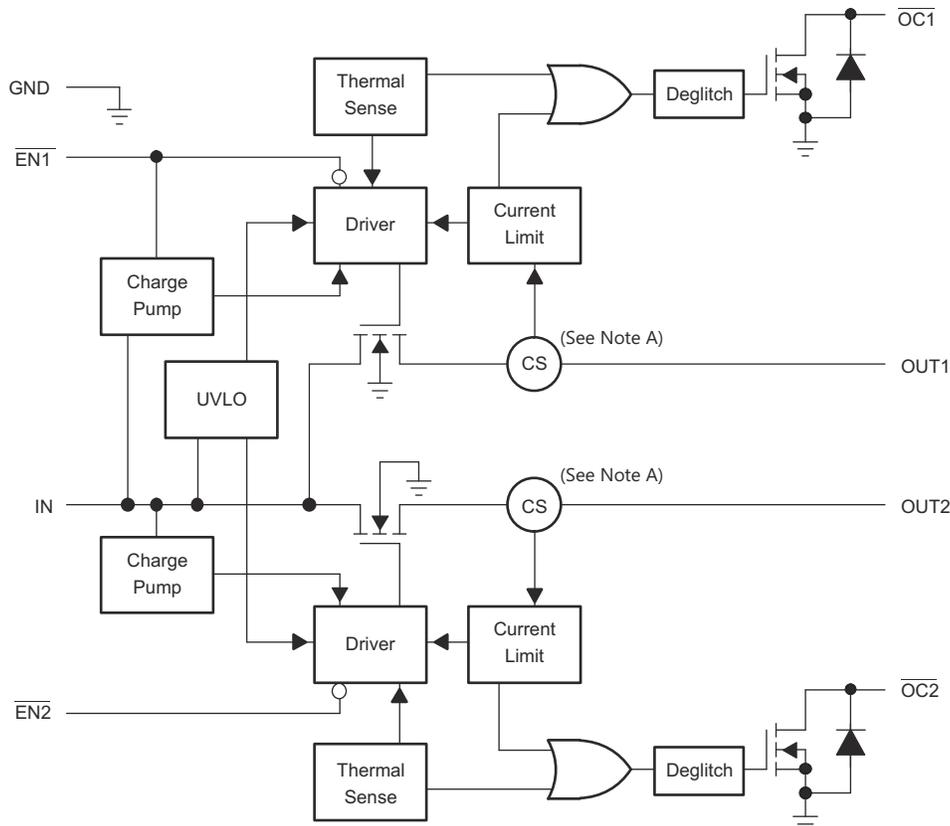
8.2 Functional Block Diagrams



Copyright © 2016, Texas Instruments Incorporated

- A. CS = Current sense
- B. EN = Active low ($\overline{\text{EN}}$) for TPS2041B-Q1; Active high (EN) for TPS2051B-Q1

8-1. Functional Block Diagram (TPS2041B-Q1 and TPS2051B-Q1)



A. CS = Current sense

8-2. Functional Block Diagram (TPS2042B-Q1)

8.3 Feature Description

8.3.1 Power Switch

The power switch is an N-channel MOSFET with a low ON-state resistance. Configured as a high-side switch, the power switch prevents current flow from OUT to IN and IN to OUT when disabled. The power switch supplies a minimum current of 500 mA.

8.3.2 Charge Pump

An internal charge pump supplies power to the driver circuit and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 2.7 V and requires little supply current.

8.3.3 Driver

The driver controls the gate voltage of the power switch. To limit large current surges and reduce the associated electromagnetic interference (EMI) produced, the driver incorporates circuitry that controls the rise times and fall times of the output voltage.

8.3.4 Enable (\overline{ENx})

The logic enable pin disables the power switch and the bias for the charge pump, driver, and other circuitry to reduce the supply current. The supply current is reduced to less than 1 μA or 2 μA when a logic high is present on \overline{EN} . A logic zero input on \overline{EN} restores bias to the drive and control circuits and turns the switch on. The enable input is compatible with both TTL and CMOS logic levels.

8.3.5 Enable (EN)

The logic enable disables the power switch and the bias for the charge pump, driver, and other circuitry to reduce the supply current. The supply current is reduced to less than 1 μA or 2 μA when a logic low is present on EN. A logic high input on EN restores bias to the drive and control circuits and turns the switch on. The enable input is compatible with both TTL and CMOS logic levels.

8.3.6 Overcurrent ($\overline{\text{OCx}}$)

The $\overline{\text{OCx}}$ open-drain output is asserted (active low) when an overcurrent or overtemperature condition is encountered. The output remains asserted until the overcurrent or overtemperature condition is removed. A 10-ms deglitch circuit prevents the $\overline{\text{OCx}}$ signal from oscillation or false triggering. If an overtemperature shutdown occurs, the $\overline{\text{OCx}}$ is asserted instantaneously.

8.3.7 Current Sense

A sense FET monitors the current supplied to the load. The sense FET measures current more efficiently than conventional resistance methods. When an overload or short circuit is encountered, the current-sense circuitry sends a control signal to the driver. The driver in turn reduces the gate voltage and drives the power FET into its saturation region, which switches the output into a constant-current mode and holds the current constant while varying the voltage on the load.

8.3.8 Thermal Sense

Thermal protection prevents damage to the IC when heavy-overload or short-circuit faults are present for extended periods of time. The TPS204xB-Q1 and TPS205xB-Q1 implement a thermal sensing to monitor the operating junction temperature of the power distribution switch. In an overcurrent or short-circuit condition, the junction temperature rises due to excessive power dissipation. Once the die temperature rises to approximately 140°C due to overcurrent conditions, the internal thermal sense circuitry turns the power switch off, thus preventing the power switch from damage. Hysteresis is built into the thermal sense circuit, and after the device has cooled approximately 10°C, the switch turns back on. The switch continues to cycle in this manner until the load fault or input power is removed. The $\overline{\text{OCx}}$ open-drain output is asserted (active low) when an overtemperature shutdown or overcurrent occurs.

8.3.9 Undervoltage Lockout (UVLO)

A voltage sense circuit monitors the input voltage. When the input voltage is below approximately 2 V, a control signal turns off the power switch.

8.4 Device Functional Modes

表 8-1 lists OUT pin state as determined by the $\overline{\text{EN}}$ pin.

表 8-1. OUT Pin State

EN	TPS2041B-Q1	TPS2042B-Q1	TPS2051B-Q1
Low	IN	Open	Open
High	Open	IN	IN

9 Application and Implementation

注

以下のアプリケーション情報は、TI の製品仕様に含まれるものではなく、TI ではその正確性または完全性を保証いたしません。個々の目的に対する製品の適合性については、お客様の責任で判断していただくこととなります。お客様は自身の設計実装を検証しテストすることで、システムの機能を確認する必要があります。

9.1 Application Information

9.1.1 Universal Serial Bus (USB) Applications

The universal serial bus (USB) interface is a 12-Mbps, or 1.5-Mbps, multiplexed serial bus designed for low-to-medium bandwidth PC peripherals (for example, keyboards, printers, scanners, and mice). The four-wire USB interface is conceived for dynamic attach-detach (hot plug-unplug) of peripherals. Two lines are provided for differential data, and two lines are provided for 5-V power distribution.

USB data is a 3.3-V level signal, but power is distributed at 5 V to allow for voltage drops in cases where power is distributed through more than one hub across long cables. Each function must provide its own regulated 3.3 V from the 5-V input or its own internal power supply.

The USB specification defines the following five classes of devices, each differentiated by power-consumption requirements:

- Hosts and self-powered hubs (SPHs)
- Bus-powered hubs (BPHs)
- Low-power bus-powered functions
- High-power bus-powered functions
- Self-powered functions

Self-powered and bus-powered hubs distribute data and power to downstream functions. The TPS204xB-Q1 and TPS205xB-Q1 can provide power-distribution solutions to many of these classes of devices.

9.2 Typical Applications

9.2.1 TPS2042B-Q1 Typical Application

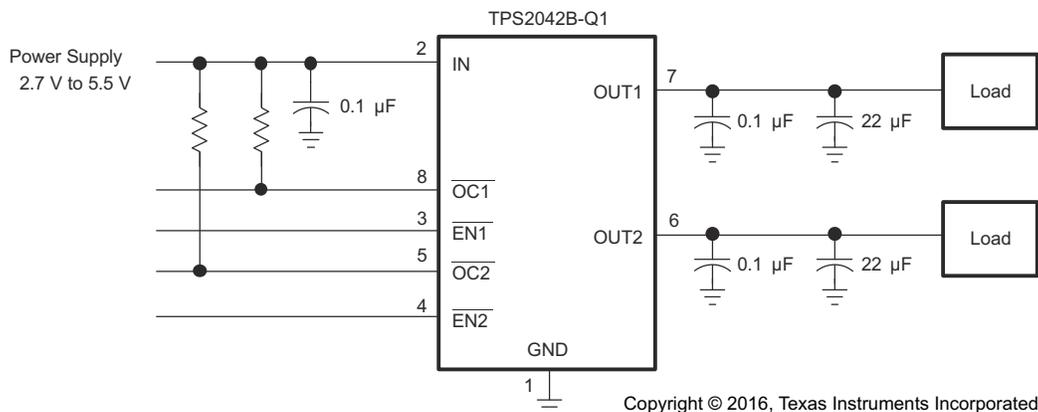


図 9-1. Typical Application Schematic Using the TPS2042B-Q1

9.2.1.1 Design Requirements

For this design example, use the parameters listed in 表 9-1 as the input parameters.

表 9-1. Design Parameters

PARAMETER	VALUE
Input voltage	5 V
Output1 voltage	5 V
Output2 voltage	5 V
Output1 current	0.5 A
Output2 current	0.5 A

9.2.1.2 Detailed Design Procedure

9.2.1.2.1 Overcurrent

A sense FET is employed to check for overcurrent conditions. Unlike current-sense resistors, sense FETs do not increase the series resistance of the current path. When an overcurrent condition is detected, the device maintains a constant output current and reduces the output voltage accordingly. Complete shutdown occurs only if the fault is present long enough to activate thermal limiting.

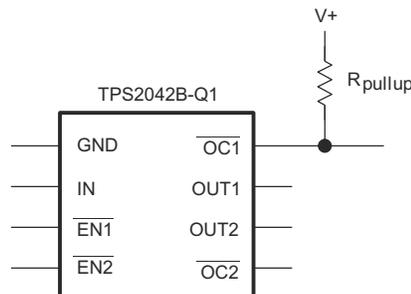
Three possible overload conditions can occur. In the first condition, the output has been shorted before the device is enabled or before $V_{I(IN)}$ has been applied (see 图 9-7 through 图 9-10). The TPS20xxB-Q1 senses the short and immediately switches into a constant-current output.

In the second condition, a short or an overload occurs while the device is enabled. At the instant the overload occurs, high currents may flow for a short period of time before the current-limit circuit can react. After the current-limit circuit has tripped (reached the overcurrent trip threshold), the device switches into constant-current mode.

In the third condition, the load has been gradually increased beyond the recommended operating current. The current is permitted to rise until the current-limit threshold is reached or until the thermal limit of the device is exceeded (see 图 6-7 through 图 6-8). The TPS20xxB-Q1 is capable of delivering current up to the current-limit threshold without damaging the device. Once the threshold has been reached, the device switches into its constant-current mode.

9.2.1.2.2 \overline{OC} Response

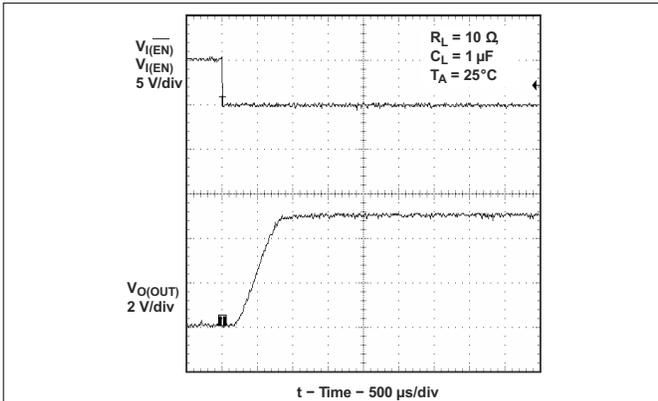
The \overline{OCx} open-drain output is asserted (active low) when an overcurrent or overtemperature shutdown condition is encountered after a 10-ms deglitch timeout. The output remains asserted until the overcurrent or overtemperature condition is removed. Connecting a heavy capacitive load to an enabled device can cause a momentary overcurrent condition; however, no false reporting on \overline{OCx} occurs due to the 10-ms deglitch circuit. The TPS20xxB-Q1 is designed to eliminate false overcurrent reporting. The internal overcurrent deglitch eliminates the need for external components to remove unwanted pulses. \overline{OCx} is not deglitched when the switch is turned off due to an overtemperature shutdown.



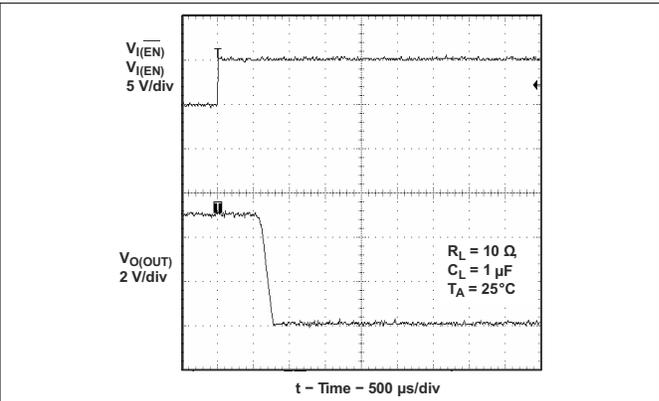
Copyright © 2016, Texas Instruments Incorporated

图 9-2. Typical Circuit for the \overline{OC} Pin (TPS2042B-Q1)

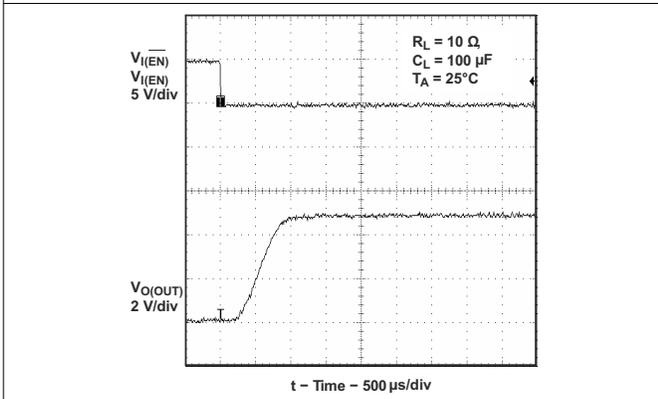
9.2.1.3 Application Curves



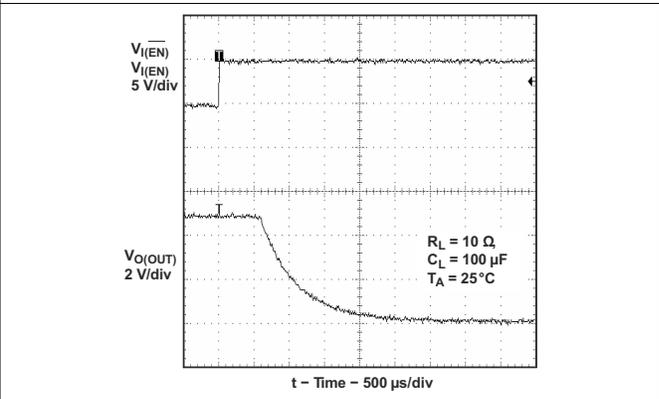
☒ 9-3. Turnon Delay and Rise Time With 1-µF Load



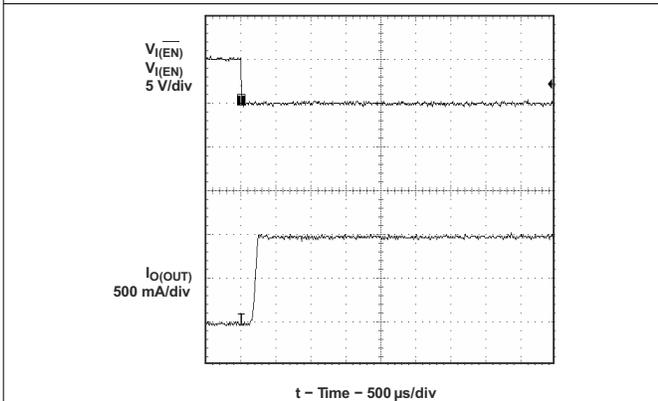
☒ 9-4. Turnoff Delay and Fall Time With 1-µF Load



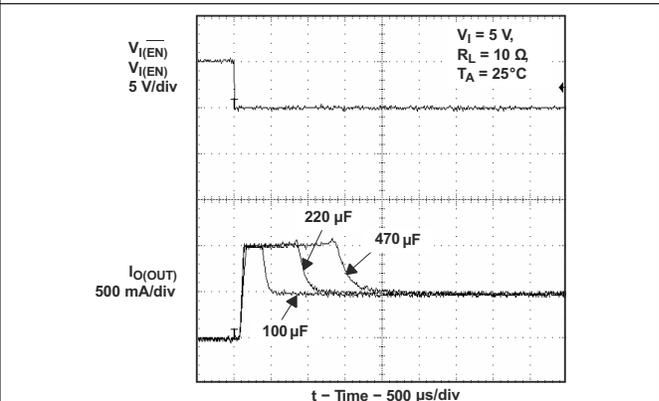
☒ 9-5. Turnon Delay and Rise Time With 100-µF Load



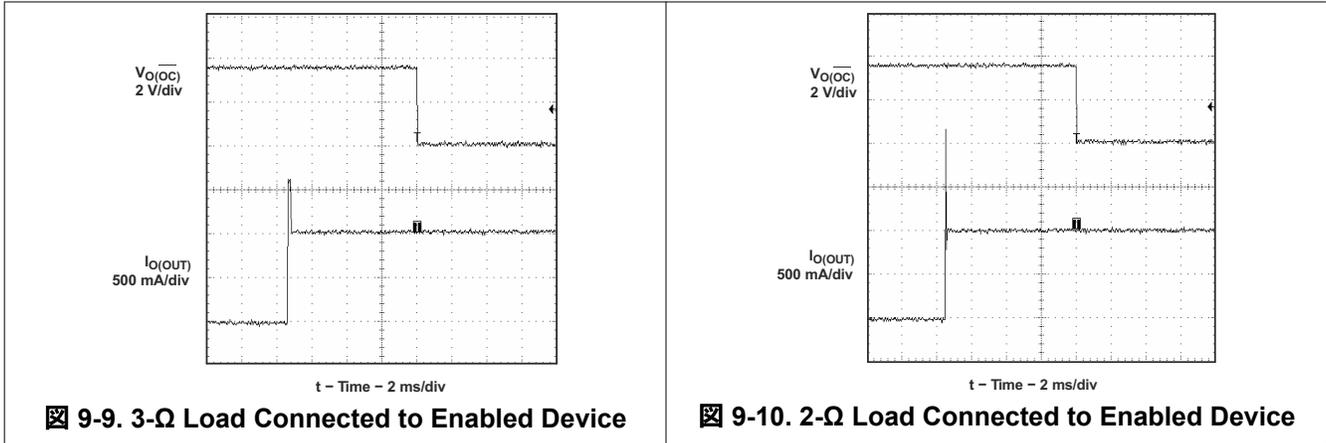
☒ 9-6. Turnoff Delay and Fall Time With 100-µF Load



☒ 9-7. Short-Circuit Current, Device Enabled Into Short

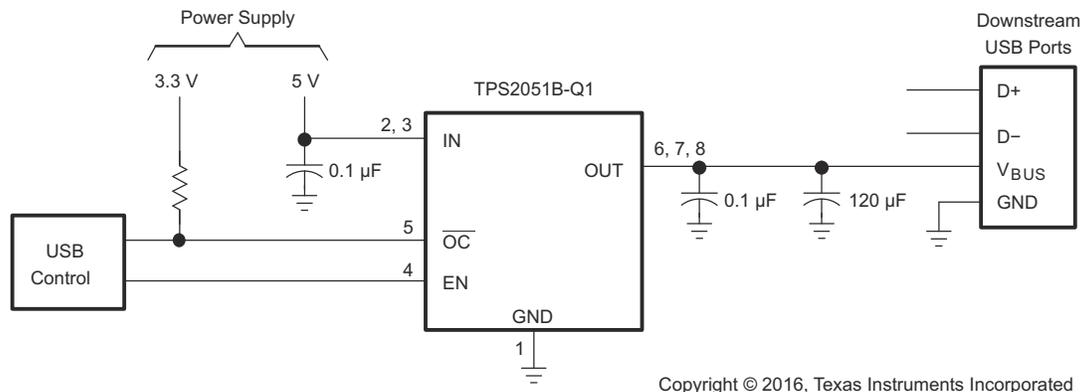


☒ 9-8. Inrush Current With Different Load Capacitance



9.2.2 Hosts and Self-Powered Hubs and Bus-Powered Hubs

Hosts and self-powered hubs have a local power supply that powers the embedded functions and the downstream ports (see 9-11). This power supply must provide from 5.25 V to 4.75 V to the board side of the downstream connection under full-load and no-load conditions. Hosts and SPHs are required to have current-limit protection and must report overcurrent conditions to the USB controller. Typical SPHs are desktop PCs, monitors, printers, and stand-alone hubs.



9-11. Typical One-Port USB Host or Self-Powered Hub

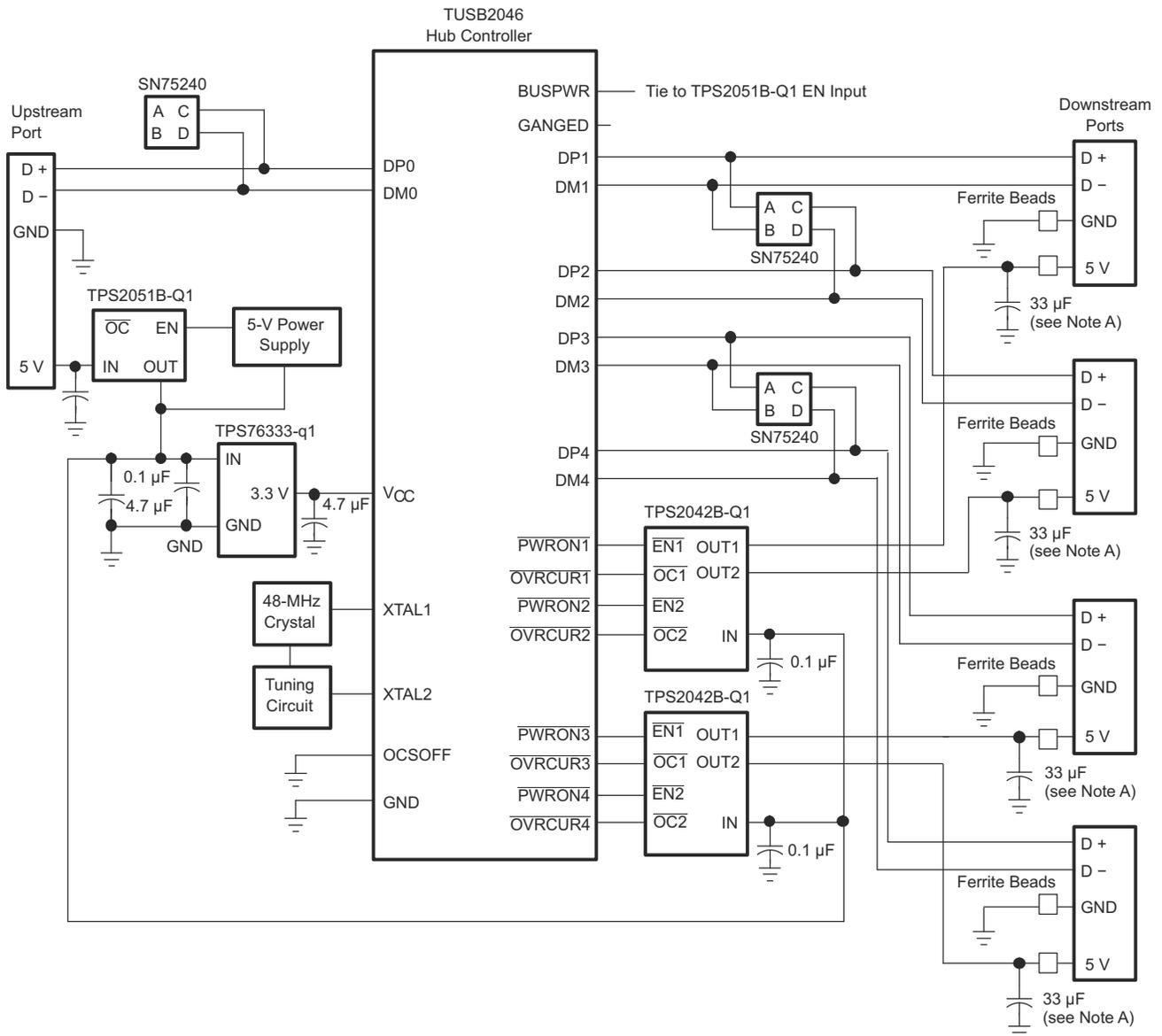
9.2.2.1 Design Requirements

9.2.2.1.1 USB Power-Distribution Requirements

USB can be implemented in several ways, and, regardless of the type of USB device being developed, several power-distribution features must be implemented.

- Hosts and self-powered hubs must:
 - Current-limit downstream ports
 - Report overcurrent conditions on USB V_{BUS}
- Bus-powered hubs must:
 - Enable and disable power to downstream ports
 - Power up at < 100 mA
 - Limit inrush current (< 44 Ω and 10 μF)
- Functions must:
 - Limit inrush currents
 - Power up at < 100 mA

The feature set of the TPS204xB-Q1 and TPS205xB-Q1 allows them to meet each of these requirements. The integrated current-limiting and overcurrent reporting is required by hosts and self-powered hubs. The logic-level



Copyright © 2016, Texas Instruments Incorporated

A. USB rev 1.1 requires 120 µF per hub.

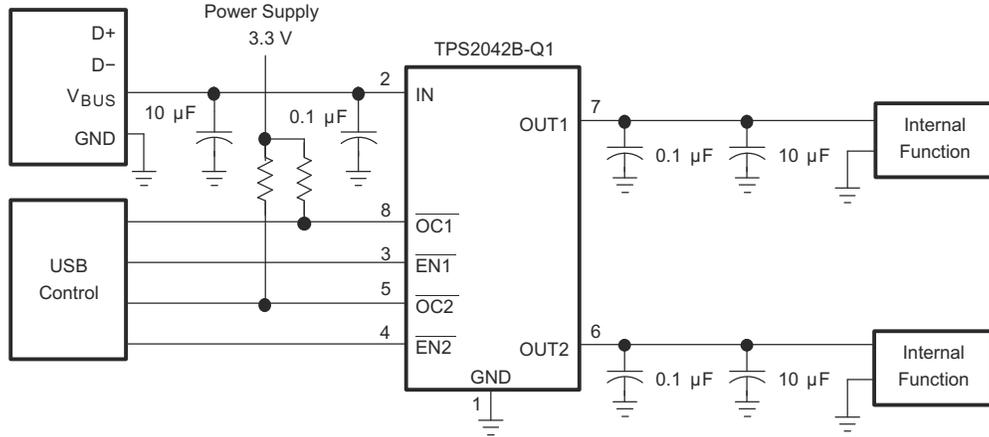
9-13. Hybrid Self-Powered or Bus-Powered Hub Implementation (TPS2042B-Q1)

9.2.2.2 Detailed Design Procedure

Bus-powered hubs obtain all power from upstream ports and often contain an embedded function. The hubs are required to power up with less than one unit load. The BPH usually has one embedded function, and power is always available to the controller of the hub. If the embedded function and hub require more than 100 mA on power up, the power to the embedded function may need to be kept off until enumeration is completed. This can be accomplished by removing power or by shutting off the clock to the embedded function. Power switching the embedded function is not necessary if the aggregate power draw for the function and controller is less than one unit load. The total current drawn by the bus-powered device is the sum of the current to the controller, the embedded function, and the downstream ports, and it is limited to 500 mA from an upstream port.

9.2.2.2.1 Low-Power Bus-Powered and High-Power Bus-Powered Functions

Both low-power and high-power bus-powered functions obtain all power from upstream ports; low-power functions always draw less than 100 mA; high-power functions must draw less than 100 mA at power up and can draw up to 500 mA after enumeration. If the load of the function is more than the parallel combination of 44 Ω and 10 μF at power up, the device must implement inrush current limiting (see [Figure 9-14](#)).

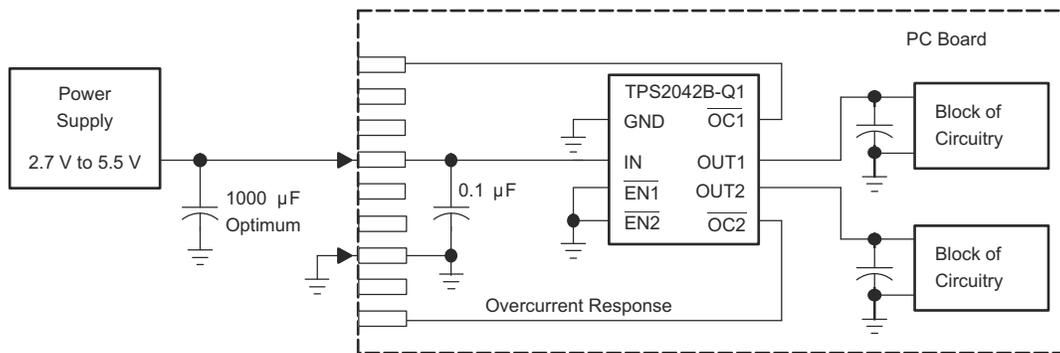


Copyright © 2016, Texas Instruments Incorporated

Figure 9-14. High-Power Bus-Powered Function (TPS2042B-Q1)

9.2.3 Generic Hot-Plug Applications

In many applications, it may be necessary to remove modules or PC boards while the main unit is still operating. These are considered hot-plug applications. Such implementations require the control of current surges seen by the main power supply and the card being inserted. The most effective way to control these surges is to limit and slowly ramp the current and voltage being applied to the card, similar to the way in which a power supply normally turns on. Due to the controlled rise and fall times of the TPS204xB-Q1 and TPS205xB-Q1, these devices can be used to provide a softer start-up to devices being hot-plugged into a powered system. The UVLO feature of the TPS204xB-Q1 and TPS205xB-Q1 also ensures that the switch is off after the card has been removed, and that the switch is off during the next insertion. The UVLO feature ensures a soft start with a controlled rise time for every insertion of the card or module.



Copyright © 2016, Texas Instruments Incorporated

Figure 9-15. Example Hot-Plug Implementation (TPS2042B-Q1)

By placing the TPS204xB-Q1 or TPS205xB-Q1 between the V_{CC} input and the rest of the circuitry, the input power reaches these devices first after insertion. The typical rise time of the switch is approximately 1 ms, providing a slow voltage ramp at the output of the device. This implementation controls system surge currents and provides a hot-plugging mechanism for any device.

9.2.3.1 Design Requirements

For this design example, use the parameters listed in 表 9-2 as the input parameters.

表 9-2. Design Parameters

PARAMETER	VALUE
Input voltage	5 V
Output1 voltage	5 V
Output2 voltage	5 V
Output1 current	0.5 A
Output2 current	0.5 A

9.2.3.2 Detailed Design Procedure

To begin the design process a few parameters must be decided upon. The designer must know the following:

- Normal input operation voltage
- Current limit

Input and output capacitance improves the performance of the device; the actual capacitance must be optimized for the particular application. For all applications, TI recommends a 0.1 μF or greater ceramic bypass capacitor between IN and GND, as close to the device as possible for local noise decoupling. This precaution reduces ringing on the input due to power-supply transients. Additional input capacitance may be required on the input to reduce voltage undershoot from exceeding the UVLO of other load share one power rail with TPS2042B-Q1 device or overshoot from exceeding the absolute-maximum voltage of the device during heavy transient conditions. This is especially important during bench testing when long, inductive cables are used to connect the evaluation board to the bench power supply. Output capacitance is not required, but TI recommends placing a high-value electrolytic capacitor on the output pin when large transient currents are expected on the output to reduce the undershoot, which is caused by the inductance of the output power bus just after a short has occurred and the TPS2042B-Q1 device has abruptly reduced OUT current. Energy stored in the inductance drives the OUT voltage down and potentially negative as it discharges.

10 Power Supply Recommendations

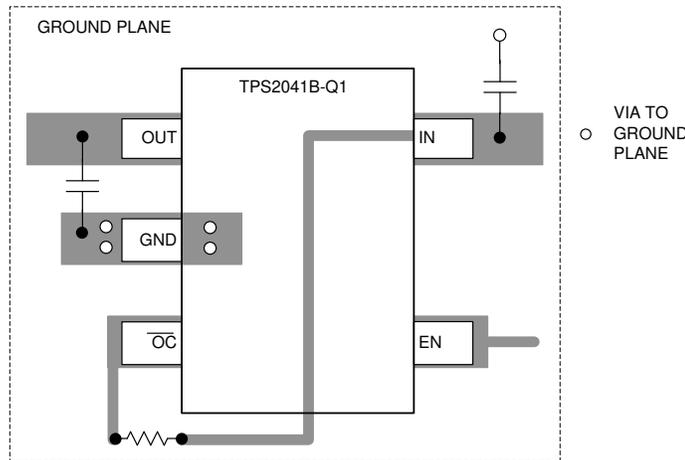
TI recommends a 0.01- μF to 0.1- μF ceramic bypass capacitor close to the device between IN and GND. TI recommends placing a high-value electrolytic capacitor on the output pins when the output load is heavy. This precaution reduces power-supply transients that may cause ringing on the input. Additionally, bypassing the output with a 0.01- μF to 0.1- μF ceramic capacitor improves the immunity of the device to short-circuit transients. See [图 9-1](#).

11 Layout

11.1 Layout Guidelines

- Place the 100-nF bypass capacitor near the IN and GND pins and make the connections using a low-inductance trace.
- TI recommends placing a high-value electrolytic capacitor and a 100-nF bypass capacitor on the output pin when large transient currents are expected on the output.

11.2 Layout Example



☒ 11-1. Layout Recommendation

11.3 Thermal Considerations

The low on-resistance on the N-channel MOSFET allows the small surface-mount packages to pass large currents. The thermal resistances of these packages are high compared to those of power packages; it is good design practice to check power dissipation and junction temperature. Begin by determining the $r_{DS(ON)}$ of the N-channel MOSFET relative to the input voltage and operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read $r_{DS(ON)}$ from ☒ 6-9. Using this value, the power dissipation per switch can be calculated by 式 1:

$$P_D = r_{DS(ON)} \times I^2 \quad (1)$$

Multiply this number by the number of switches being used. This step renders the total power dissipation from the N-channel MOSFETs.

Finally, calculate the junction temperature with 式 2:

$$T_J = P_D \times R_{\theta JA} + T_A \quad (2)$$

where

- T_A = Ambient temperature °C
- $R_{\theta JA}$ = Thermal resistance
- P_D = Total power dissipation based on number of switches being used.

Compare the calculated junction temperature with the initial estimate. If they do not agree within a few degrees, repeat the calculation, using the calculated value as the new estimate. Two or three iterations are generally sufficient to get a reasonable answer.

12 Device and Documentation Support

12.1 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

表 12-1. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
TPS2041B-Q1	Click here				
TPS2042B-Q1	Click here				
TPS2051B-Q1	Click here				

12.2 ドキュメントの更新通知を受け取る方法

ドキュメントの更新についての通知を受け取るには、[ti.com](#) のデバイス製品フォルダを開いてください。「更新の通知を受け取る」をクリックして登録すると、変更されたすべての製品情報に関するダイジェストを毎週受け取れます。変更の詳細については、修正されたドキュメントに含まれている改訂履歴をご覧ください。

12.3 サポート・リソース

TI E2E™ サポート・フォーラムは、エンジニアが検証済みの回答と設計に関するヒントをエキスパートから迅速かつ直接得ることができる場所です。既存の回答を検索したり、独自の質問をしたりすることで、設計に必要な支援を迅速に得ることができます。

リンクされているコンテンツは、該当する貢献者により、現状のまま提供されるものです。これらは TI の仕様を構成するものではなく、必ずしも TI の見解を反映したものではありません。TI の[使用条件](#)を参照してください。

12.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

すべての商標は、それぞれの所有者に帰属します。

12.5 静電気放電に関する注意事項



この IC は、ESD によって破損する可能性があります。テキサス・インスツルメンツは、IC を取り扱う際には常に適切な注意を払うことを推奨します。正しい ESD 対策をとらないと、デバイスを破損するおそれがあります。

ESD による破損は、わずかな性能低下からデバイスの完全な故障まで多岐にわたります。精密な IC の場合、パラメータがわずかに変化するだけで公表されている仕様から外れる可能性があるため、破損が発生しやすくなっています。

12.6 用語集

TI 用語集 この用語集には、用語や略語の一覧および定義が記載されています。

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TPS2041BQDBVRQ1	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	PLIQ	Samples
TPS2042BQDRQ1	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2042B	Samples
TPS2051BQDRQ1	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	2051BQ	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

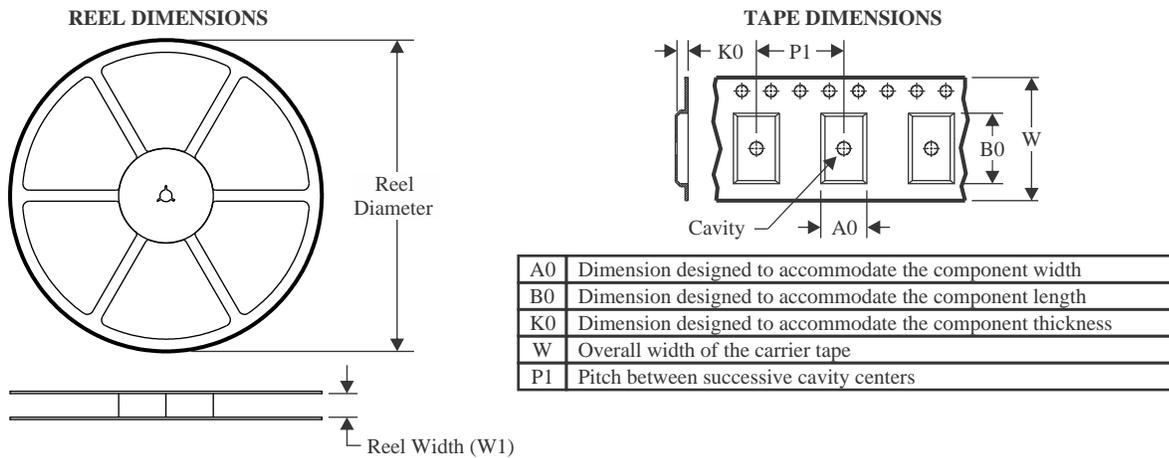
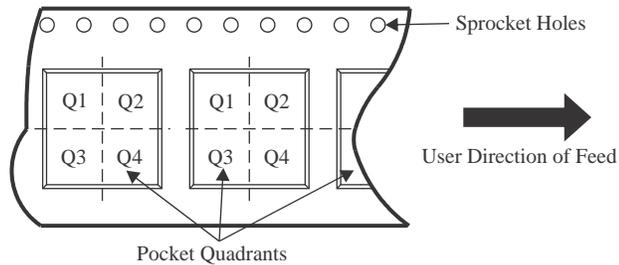
(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

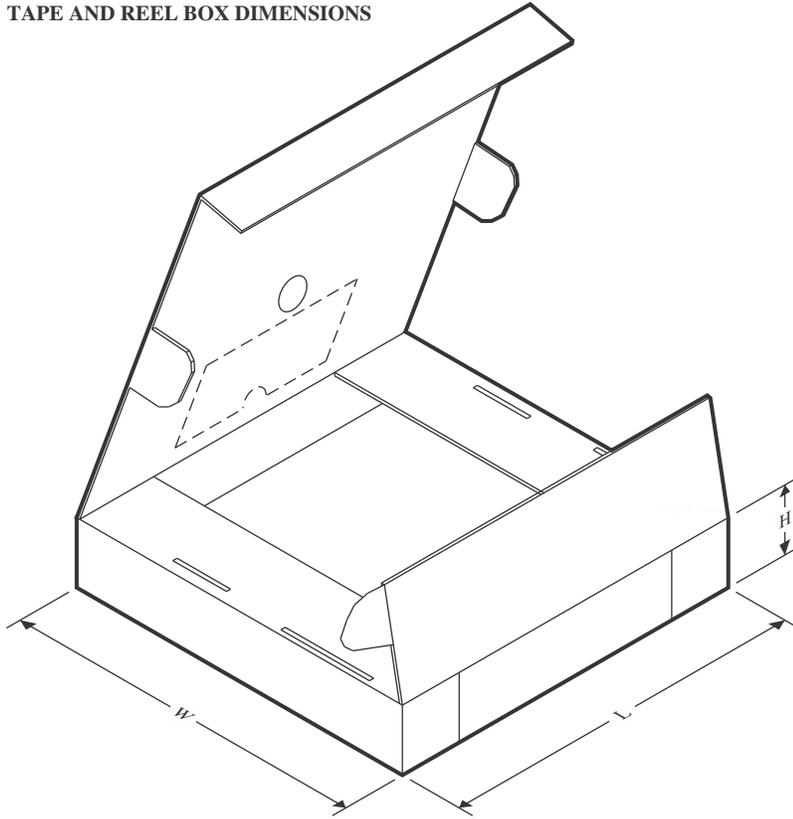
Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS2041BQDBVRQ1	SOT-23	DBV	5	3000	179.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS2042BQDRQ1	SOIC	D	8	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
TPS2051BQDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS2041BQDBVRQ1	SOT-23	DBV	5	3000	200.0	183.0	25.0
TPS2042BQDRQ1	SOIC	D	8	2500	340.5	338.1	20.6
TPS2051BQDRQ1	SOIC	D	8	2500	340.5	338.1	20.6

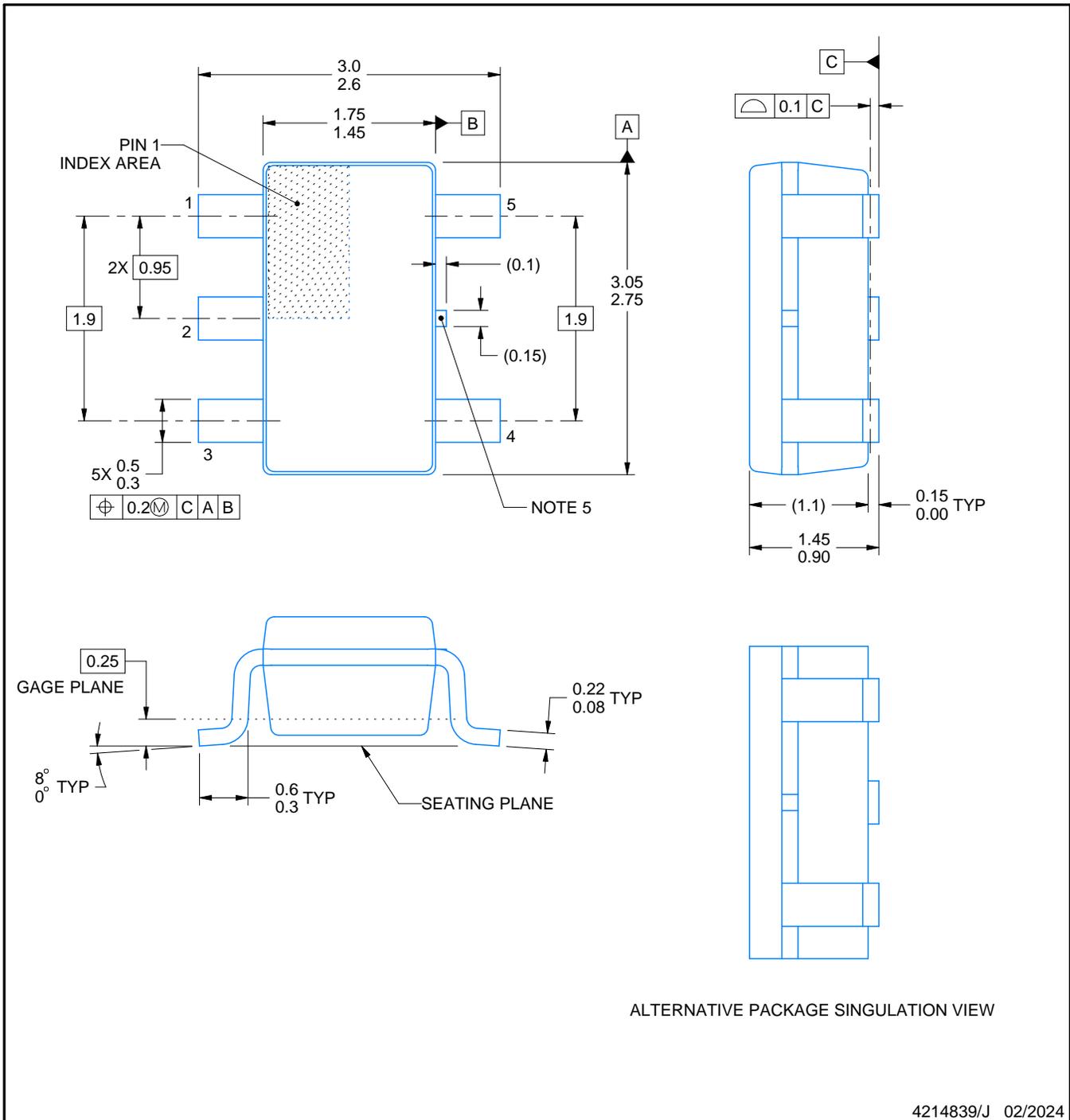
DBV0005A



PACKAGE OUTLINE

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



4214839/J 02/2024

NOTES:

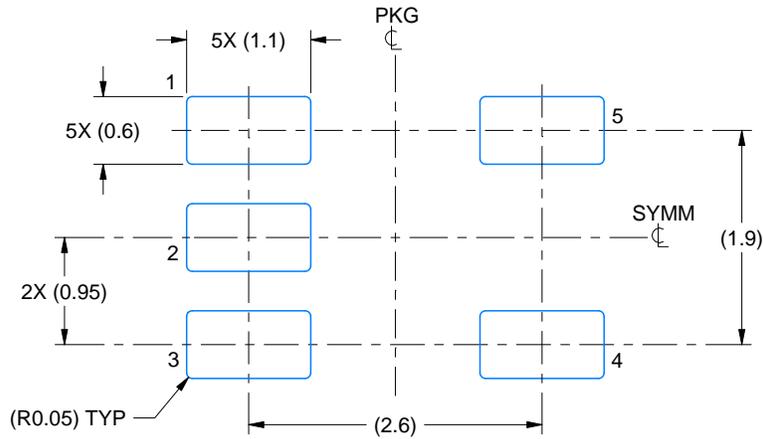
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Reference JEDEC MO-178.
4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
5. Support pin may differ or may not be present.

EXAMPLE BOARD LAYOUT

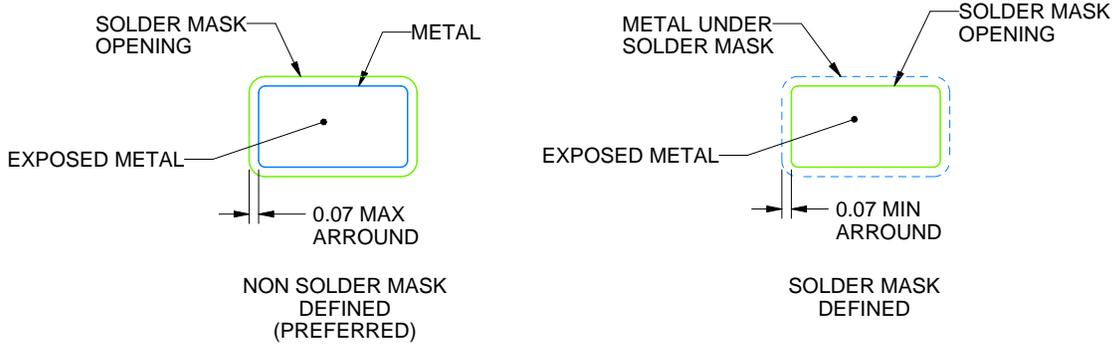
DBV0005A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:15X



SOLDER MASK DETAILS

4214839/J 02/2024

NOTES: (continued)

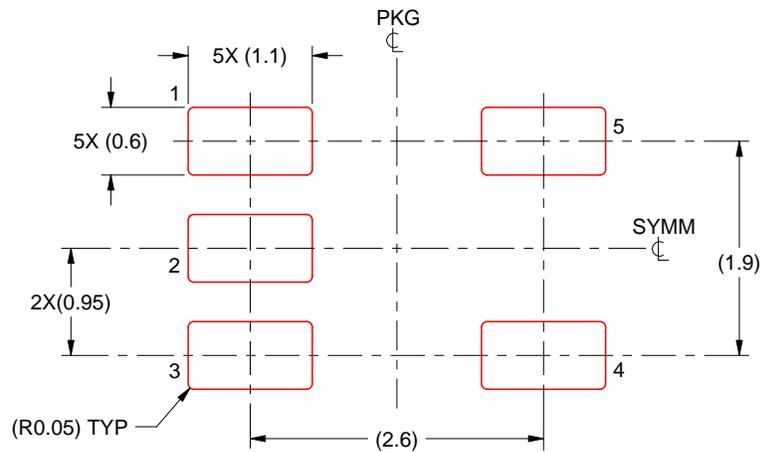
- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DBV0005A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR

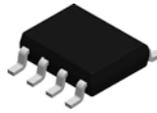


SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:15X

4214839/J 02/2024

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

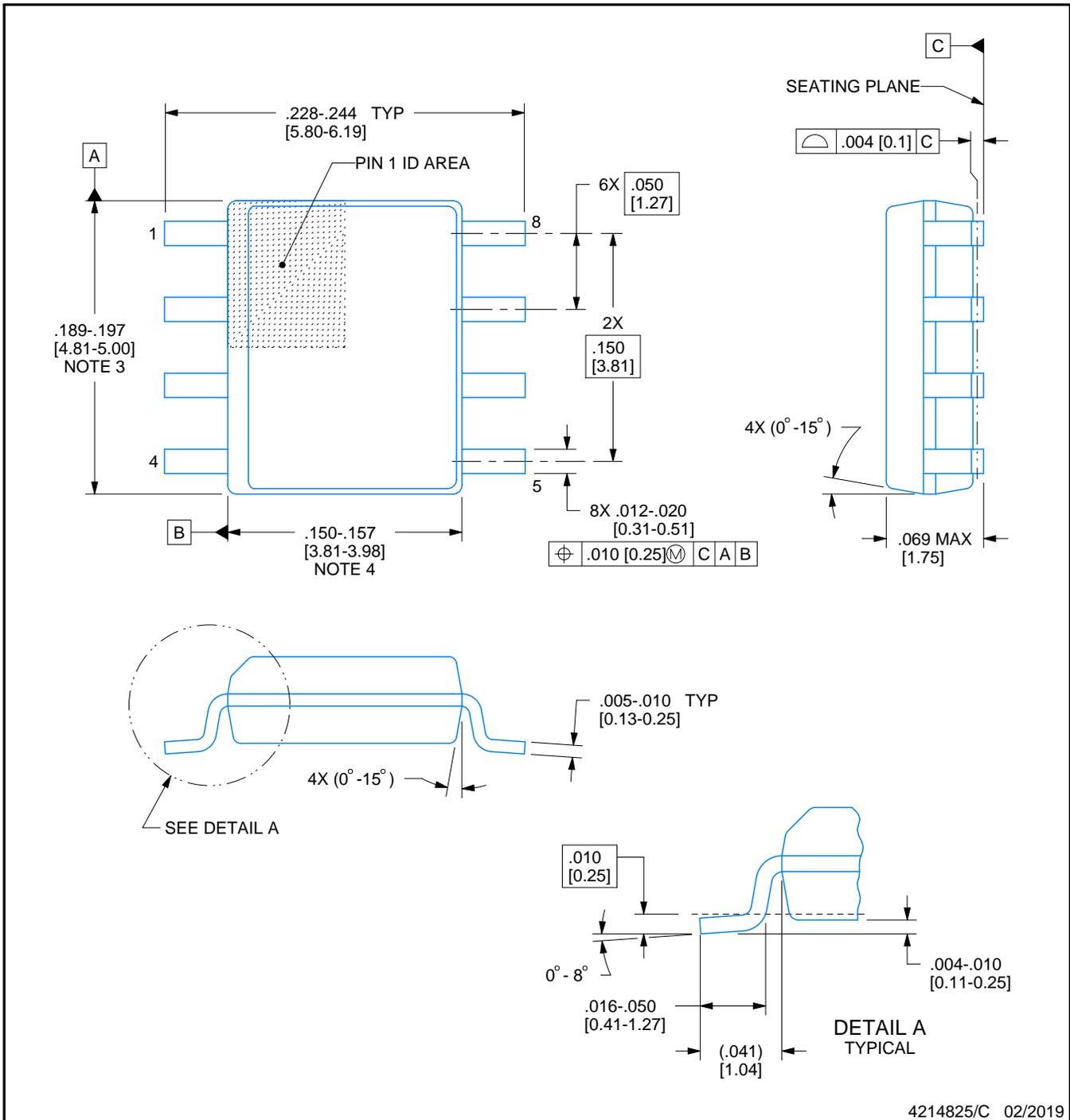


D0008A

PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



4214825/C 02/2019

NOTES:

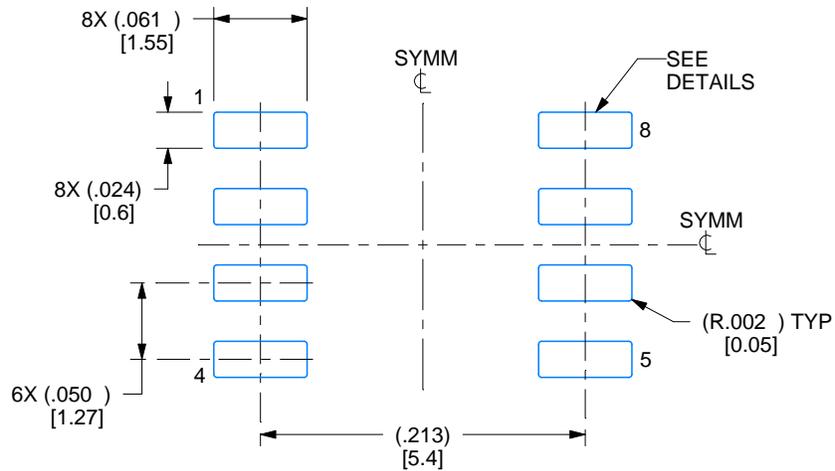
1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed $.006$ [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.

EXAMPLE BOARD LAYOUT

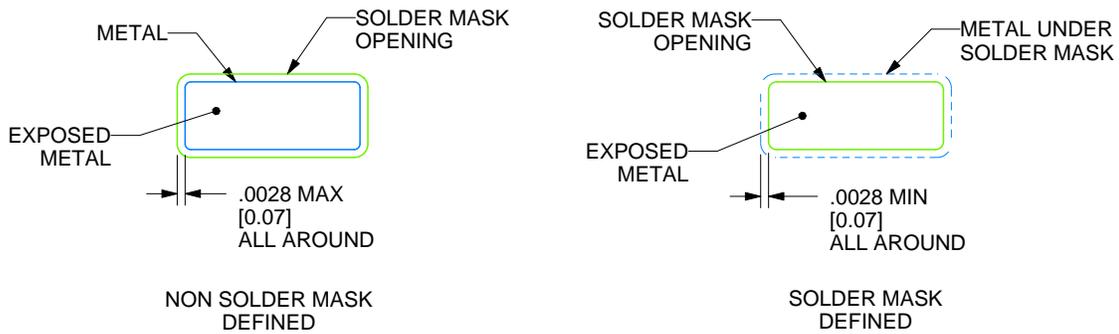
D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

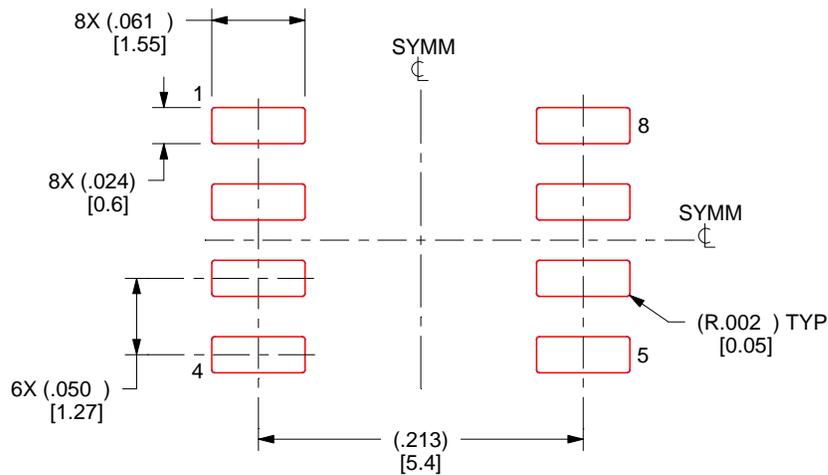
- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE:8X

4214825/C 02/2019

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

重要なお知らせと免責事項

TI は、技術データと信頼性データ (データシートを含みます)、設計リソース (リファレンス・デザインを含みます)、アプリケーションや設計に関する各種アドバイス、Web ツール、安全性情報、その他のリソースを、欠陥が存在する可能性のある「現状のまま」提供しており、商品性および特定目的に対する適合性の黙示保証、第三者の知的財産権の非侵害保証を含むいかなる保証も、明示的または黙示的にかかわらず拒否します。

これらのリソースは、TI 製品を使用する設計の経験を積んだ開発者への提供を意図したものです。(1) お客様のアプリケーションに適した TI 製品の選定、(2) お客様のアプリケーションの設計、検証、試験、(3) お客様のアプリケーションに該当する各種規格や、その他のあらゆる安全性、セキュリティ、規制、または他の要件への確実な適合に関する責任を、お客様のみが単独で負うものとし、

上記の各種リソースは、予告なく変更される可能性があります。これらのリソースは、リソースで説明されている TI 製品を使用するアプリケーションの開発の目的でのみ、TI はその使用をお客様に許諾します。これらのリソースに関して、他の目的で複製することや掲載することは禁止されています。TI や第三者の知的財産権のライセンスが付与されている訳ではありません。お客様は、これらのリソースを自身で使用した結果発生するあらゆる申し立て、損害、費用、損失、責任について、TI およびその代理人を完全に補償するものとし、TI は一切の責任を拒否します。

TI の製品は、[TI の販売条件](#)、または [ti.com](#) やかかる TI 製品の関連資料などのいずれかを通じて提供する適用可能な条項の下で提供されています。TI がこれらのリソースを提供することは、適用される TI の保証または他の保証の放棄の拡大や変更を意味するものではありません。

お客様がいかなる追加条項または代替条項を提案した場合でも、TI はそれらに異議を唱え、拒否します。

郵送先住所 : Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
Copyright © 2024, Texas Instruments Incorporated